## Notice of References Cited Application/Control No. 10/040,558 Examiner Richard Lee Applicant(s)/Patent Under Reexamination HSU, CHIUN-WEN Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,089,889 A	02-1992	Sugiyama, Kenji	375/240.12
	В	US-2003/0086496 A1	05-2003	Zhang et al.	375/240.16
	С	US-2002/0036705 A1	03-2002	Lee et al.	348/459
	D	US-5,280,350 A	01-1994	DeHaan et al.	348/699
	Е	US-5,072,293	12-1991	De Haan et al.	348/699
	F	US-5,978,047 A	11-1999	May, Robert Edward	348/616
	G	US-4,890,160	12-1989	Thomas, Graham A.	348/699
	Н	US-6,026,190 A	02-2000	Astle, Brian	382/232
	I	US-2002/0171759 A1	11-2002	Handjojo et al.	348/452
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	Q					
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	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.